

2N1959 (SILICON)



CASE 31
(TO-5)

NPN silicon annular transistor designed for high-speed, medium-power saturated switching applications.

Collector connected to case

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage $R_{BE} = 10$ ohms	V_{CER}	40	Vdc
Collector-Base Voltage	V_{CB}	60	Vdc
Emitter-Base Voltage	V_{EB}	5	Vdc
Collector Current	I_C	500	mAdc
Total Device Dissipation @ $T_A = 25^{\circ}C$ Derate above $25^{\circ}C$	P_D	600 4.0	mW mW/ $^{\circ}C$
Total Device Dissipation @ $T_C = 25^{\circ}C$ Derate above $25^{\circ}C$	P_D	2.0 1.3	Watts mW/ $^{\circ}C$
Operating Junction Temperature Range	T_J	-65 to +175	$^{\circ}C$
Storage Temperature Range	T_{stg}	-65 to +200	$^{\circ}C$

2N1959 (continued)

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Collector-Emitter Breakdown Voltage ($I_C = 50 \mu\text{A dc}$, $R_{BE} = 10 \text{ ohms}$)	BV_{CER}	40	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 100 \mu\text{A dc}$, $I_E = 0$)	BV_{CBO}	60	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 100 \mu\text{A dc}$, $I_C = 0$)	BV_{EBO}	5.0	—	Vdc
Collector Cutoff Current ($V_{CB} = 30 \text{ Vdc}$, $I_E = 0$) ($V_{CB} = 30 \text{ Vdc}$, $I_E = 0$, $T_A = 150^\circ\text{C}$)	I_{CBO}	—	0.5 300	$\mu\text{A dc}$

ON CHARACTERISTICS

DC Current Gain ($I_C = 150 \text{ mA dc}$, $V_{CE} = 10 \text{ Vdc}$)	h_{FE}	40	120	—
Collector-Emitter Saturation Voltage ($I_C = 150 \text{ mA dc}$, $I_B = 15 \text{ mA dc}$)	$V_{CE(sat)}$	—	0.45	Vdc
Base-Emitter Saturation Voltage ($I_C = 150 \text{ mA dc}$, $I_B = 15 \text{ mA dc}$)	$V_{BE(sat)}$	—	1.3	Vdc

DYNAMIC CHARACTERISTICS

Current-Gain-Bandwidth Product ($I_C = 25 \text{ mA dc}$, $V_{CB} = 10 \text{ Vdc}$, $f = 100 \text{ MHz}$)	f_T	100	—	MHz	
Output Capacitance ($V_{CB} = 10 \text{ Vdc}$, $I_E = 0$, $f = 1 \text{ MHz}$)	C_{ob}	—	18	pF	
Turn-On Time	Figure 1 ($V_{CC} = 7 \text{ Vdc}$, $I_C = 150 \text{ mA dc}$, $I_{B1} = I_{B2} = 15 \text{ mA dc}$)	t_{on}	—	65	ns
Turn-Off Time		t_{off}	—	45	ns
Storage Time		t_s	—	25	ns

* t_{on} , t_{off} , and t_s measured from 50% point of input pulse.

FIGURE 1 — SWITCHING TIME TEST CIRCUIT

